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Commission on Crystallographic Apparatus

Microdensitometer Project Report I. Inter-Experimental Agreement

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Abstract

The aim of the Microdensitometer Project was to investigate the agreement between intensity measurements performed by different laboratories. Each of fifteen participants was provided with four precession films prepared from two different crystals of sodium tartrate dihydrate: two films (Aand B) of different exposure times from a small crystal and two similar films (C and D) from a larger crystal. A total of 33000 measured intensities and, in addition, 17000 scaled intensities were submitted for analysis.

The inter-film factor between films A and B and C and D was timed to be 3.0 and the average values obtained from the different data sets were 2.90 and 3.00, respectively. The processing of these data sets included an analysis of the spread of intensities for symmetry-related reflections both within any one experiment and between experiments. In addition, a calculation using the analysis of variance technique has been made based on the weighted deviations of intensities from the set of mean values in order to locate errors from various sources. By using an R_{sym} value defined later in the text as

$$R_{\rm sym} = \frac{\sum\limits_{hk} \sum\limits_{s} |I_{hk,s} - I_{hk}|}{\sum\limits_{hk} S I_{hk}} \,, \label{eq:Rsym}$$

the internal consistency within each experiment was evaluated from the *mm* symmetry in the film plane. The values of R_{sym} were found to lie in the ranges 0.055–0.102 and 0.043–0.073 for the *A* and *C* films respectively. R_{sym} values obtained from the average data sets constructed from the participants' scaled data, *B* to *A* and *D* to *C*, were 0.057 and 0.050 respectively. R_{mut} values were obtained by scaling the data sets in pairs using the scaling procedure of Hamilton, Rollett & Sparks (1965). The R_{mut} value was then defined as

$$R_{\text{mut}} = \sum_{hk} |I_i - I_j| / \sum_{hk} |I_i + I_j|$$

for experiments *i* and *j*; the range of observed values varied between 0.047 and 0.266 for the scaled data sets *B* to *A*, and between 0.039 and 0.143 for the scaled data sets *D* to *C*. It is clearly demonstrated in this report that the statistical spread of the intensities from films with small spots (A,B) is greater than that from films with large spots (C,D). It is important to note that the upper limit of measured optical density for a relevant estimate of the optical density is dependent on the size of the reflection; an upper limit of optical density which has proved useful for large reflections may be too high for small reflections.

This investigation has shown that the use of large computers (as usually found in off-line processing) may give more consistent data due to the possibility of using more extensive program systems. The report also includes a comparison of different types of linearity corrections, i. e. the use of either parabolic scaling or numerical correction of each density value, showing that the latter procedure on average gives slighty better agreement. It is difficult to draw definite conclusions about the light-beam size within this investigation, since only two participants use a small raster size (50 \times 50 μ m) for the measurement of the A and B films. However, their results indicate an improvement when the raster size is lowered. A comparison between different types of microdensitometers could not be performed as 12 of the 15 participating laboratories used the same microdensitometer model and the remaining three were all different. The real distribution of the intensities has been used as a basis for the comparison of different ways of estimating $\sigma(I)$. None of the formulae currently used could fully account for the real statistical spread. Finally, it may be concluded that the average microdensitometer system within this project gives X-ray diffraction data at a high level of accuracy, comparable with the results of the previous diffractometer project Abrahams, Hamilton & Mathieson (1970). Acta Cryst. A26, 1-18].

Introduction

In 1969 the International Union of Crystallography's Commission on Crystallographic Apparatus presented the results of the Single Crystal Intensity Measurement Project (Abrahams, Hamilton & Mathieson, 1970) whose goal had been to obtain a comprehensive picture of the accuracy of intensity measurements using diffractometers and diffractometer systems. During the 10th International Crystallographic Congress in Amsterdam in 1975, a similar project was suggested for microdensitometers, the results to be presented at the 11th Congress in Warsaw, 1978.

During September 1976 about 80 laboratories were invited to participate in the project. The 34 who expressed a willingness to contribute data to the project using their normal routine procedures were sent a questionnaire, two multiple precession films (A, B) and an intensity scale. Subsequently, they received a second film set (C, D), previously measured in a different laboratory. Each participant was requested to submit a data set from each film, containing the Miller indices, *hkl*, the integrated intensity, *I*, the position of the reflection (x, y) in film coordinates along \mathbf{a}^* and \mathbf{b}^* , respectively, and the standard deviation, $\sigma(I)$, based on the measured distribution of optical density. The submission of film coordinates, (x, y), and $\sigma(I)$ was optional. In addition, scaled data sets (*E* from films *A* and *B*, and *F* from films *C* and *D*), resulting from the user's normal scaling procedure, and, if possible, standard deviations for the averaged intensities were requested. After having received the first set, 18 laboratories reported that either the software (10) or the hardware (8) was not working satisfactorily. 15 laboratories submitted measurements from all films and completed the questionnaires.

Data from all participants were received by the end of March 1977. A preliminary analysis of the mutual and internal consistencies was performed and presented at an Open Commission Meeting during the Fourth European Crystallographic Meeting in Oxford, August 1977 (ECM-4), at which time the Commission on Crystallographic Apparatus invited other laboratories to participate. However, no other laboratories expressed any interest. The participants in the project are listed alphabetically in Table 1, but this list is not correlated in any way with the data in the subsequent tables of the report.

So that as many as possible could participate in the project, precession geometry was chosen. In order to obtain good quality films, the crystal had to be stable during exposure. For consistency analysis *mm* symmetry is desirable in the plane of the film. Furthermore, the axes in the plane of the film must be long enough to give a sufficient number of reflections in each quadrant for statistical treatment. Absorption and other diffraction effects should be small and the specimen shape selected so as not to disturb the symmetry relations. The substance finally chosen for the project was sodium tartrate dihydrate, $C_4H_4Na_2O_6.2H_2O$, which crystallizes in $P2_12_12_1$ with a = 11.460 (5), b = 14.670 (5) and c = 4.959 (3) Å (Ambady & Kartha, 1968). In the production of the films, the *c* axis was chosen as the precession axis, thus giving *hk*0 films.

Graphite-monochromated Mo $K\alpha$ radiation, a crystal-tofilm distance of 60 mm and a precession angle of 24[°] gave a total of about 800 reflections per film. Film A (9 h exposure) and film B (3 h exposure) were obtained from a crystal of

Table. 1. Participants in the IUCr Microdensitometer Project

Buehner, M. & Metter, M.
Chirgadze, Y. N., Nikonov, S. V. & Kuzin, A. P.
Cohen, G., Navia, M. A. & Davies, D. R.
Cygler, M.
Elder, M. & Machin, P.
Lindqvist, O., Olsson, G. & Sjölin, L.
Moffat, I. K., Siegel, B. M. & Szebenyi, D. M
Muirhead, H.
Nyborg, J. & La Cour, T.
Perlo, A. & Wyckoff, H. W.
Reeke, G. N., Becker, J. W. & Edelman, G. M.
Schoone, I. C.
Sherfinsky, I. S. & Rich, A.
Starkey, J.
Werner, P. E.

Zentralbau Chemie, University of Würzburg, Federal Republic of Germany Institute of Protein Research, Academy of Sciences of USSR, Moscow, USSR National Institutes of Health, Bethesda, MD, USA Institute of Chemistry, University of Lódz, Novotki, Poland SRC Microdensitometer Service, Warrington, England Institute of Inorganic Chemistry, University of Göteborg, Göteborg, Sweden Section of Biochemistry, Cornell University, Ithaca, NY, USA Dept of Biochemistry, University of Bristol, Bristol, England Institute of Chemistry, University of Aarhus, Aarhus, Denmark Dept of Molecular Biophysics and Biochemistry, Yale Station, New Haven, USA Lab. of Molecular and Developmental Biology, The Rockefeller University, NY. USA Universiteit Utrecht, Utrecht, The Netherlands Lab. of Molecular Structure, Cambridge, MA, USA Dept of Geology, University of Western Ontario, Ontario, Canada Arrhenius Lab., University of Stockholm, Stockholm, Sweden



Fig. 1. A and C precession films used in the IUCr Microdensitometer Project, showing the amount of shielding due to the beam stopper.

dimensions $0.3 \times 0.4 \times 0.12$ mm, while a crystal of dimensions $0.6 \times 0.8 \times 0.4$ mm was used for the production of films $C(1\frac{1}{2}h)$ exposure) and $D(\frac{1}{2}h)$ exposure) (cf. Fig. 1). The reflection profiles are shown in Table 2. In addition, an intensity scale was prepared by timed exposure of the attenuated primary beam. Ilford Industrial G X-ray films from the same production batch were used and efforts were made to develop all films under uniform conditions. Accidental variations in intensity on the films ought to become apparent during the analysis, since, in general, each film set (both A/B and C/D) was sent to two different laboratories. No such variation has yet been detected. Since geometrical difficulties prevented the use of a flying beam stop, a normal beam stop was used, the arm of which partially or totally shielded some reflections. The amount of shielding on films A and C can be seen in Fig. 1.

A total of 35 reflections for the A/B films and 37 reflections for the C/D films, distributed mainly between two quadrants, have been rejected from each data set before analysis, although not always by the participants.

The present report deals with the inter-experimental agreement. Report II, which will be published subsequently, will be based on comparison of the film data with diffractometer data and on structure refinement using the submitted film intensities.

Experimental procedures

A summary of some general items of information obtained from the questionnaires is given in Tables 3 and 4. The data submitted by each of the participants has been assigned an identification number, which serves as a reference in the remainder of the report. Optronics P-1000 microdensitometers were used by 12 laboratories, while the other three used a Schnell photometer III, a Saab Mark II and a Syntex AD-1 microdensitometer. The computers used for the processing and evaluation work varied considerably. Five of the systems used an off-line computer, i.e. one which is not connected to the microdensitometer. In these cases magnetic tape was generally used for intermediate data storage. There were nine on-line systems, in which the evaluation of each integrated intensity took place immediately after reading the corresponding optical densities. One participant used a manual microdensitometer. As is seen from Table 3, the speed of the evaluation is usually a function of the core capacity of the computer.

Table 4 shows the choice of scanning area for the different films A/B and C/D. The method used to determine the orientation matrix is also indicated. Most laboratories perform a least-squares refinement using 4-24 manually indexed reflections.

There are three main methods which have been used in microdensitometry to correct for the non-linearity dependence of the intensity on the measured optical density: (1) parabolic scaling of a film pack; (2) direct biasing of the microdensitometer logarithmic amplifier circuit; (3) numerical correction of each density value based on previous calibration against an intensity scale.

The non-linearity compensation given in Table 4 divides the laboratories into two groups. Laboratories 11, 12, 13, 14 and 15 used the parabolic scaling procedure for the two successive films in each film pack (method 1). The other laboratories applied a non-linearity correction to each density measurement either from calibration charts or by some mathematical function obtained from measurements on a standard intensity scale (method 2). Scale factors and scaling

Table 2. Print-out from a microdensitometer of a weak, medium and strong reflection

 σ is calculated according to the formula used by participant no. 6 (cf. Table 4).

(a)	A İll	m										-				
$ \begin{array}{r} 19\\20\\21\\24\\20\\21\\21\\22\\19\\21\\20\\21\\20\\H= \end{array} $	19 19 20 19 22 20 20 21 21 20 22 21 21 21 21 - 5	$20 \\ 22 \\ 22 \\ 20 \\ 19 \\ 22 \\ 19 \\ 19 \\ 20 \\ 19 \\ 19 \\ 19 \\ 18 \\ 19 \\ K = -$	21 20 21 19 19 22 20 19 20 19 20 21 -3	$21 \\ 22 \\ 21 \\ 22 \\ 19 \\ 21 \\ 20 \\ 20 \\ 21 \\ 22 \\ 19 \\ 20 \\ 1 = 0$	21 21 22 21 22 22 22 22 21 20 20 20 20 1NT	22 19 20 21 25 22 20 23 20 20 20 20 20 20 20	19 22 21 22 25 26 22 20 19 22 22 19 17Y =	19 23 22 21 22 24 26 23 24 20 20 20 20 20 20	$\begin{array}{c} 20\\ 20\\ 20\\ 22\\ 22\\ 23\\ 23\\ 25\\ 20\\ 18\\ 22\\ 20\\ 21\\ \sigma=2 \end{array}$	19 20 20 20 21 21 22 18 19 21 19 20 3	19 22 21 22 21 19 22 20 20 20 21 20	22 19 21 20 19 20 19 21 19 21 20 23 20	20 20 20 18 21 20 20 22 20 22 20 22 20 24 20	20 18 20 19 20 19 20 19 19 20 20 20 21	21 20 21 22 19 20 19 19 20 19 20 19 20 19 20 19 21	20 22 19 23 21 18 20 20 21 22 21 21 19
$\begin{array}{c} 21 \\ 20 \\ 20 \\ 21 \\ 19 \\ 23 \\ 22 \\ 20 \\ 21 \\ 21 \\ 21 \\ 21 \\ 21 \\ H = \end{array}$	22 21 22 21 23 22 21 23 22 21 22 21 22 21 23 19 0 <i>K</i>	$22 \\ 22 \\ 22 \\ 21 \\ 21 \\ 21 \\ 22 \\ 23 \\ 24 \\ 21 \\ 23 \\ 23 \\ = -6$	22 20 25 20 22 21 22 24 23 21 22 24 23 21 22 24 23 21 22 24 23 21	21 23 24 24 24 27 27 24 22 20 23 0 1	23 23 27 33 40 53 44 30 22 21 21 21 21 21 NTE	22 22 23 28 49 84 113 93 44 25 21 20 21 NSIT	$22 \\ 22 \\ 22 \\ 31 \\ 62 \\ 116 \\ 160 \\ 150 \\ 70 \\ 32 \\ 22 \\ 21 \\ Y = 19$	20 21 25 30 58 117 158 151 76 35 24 21 22 250	$20 \\ 22 \\ 22 \\ 25 \\ 46 \\ 79 \\ 113 \\ 96 \\ 53 \\ 31 \\ 26 \\ 22 \\ 20 \\ \sigma = 28$	22 22 21 23 30 38 49 47 33 28 25 24 23	22 20 23 23 22 24 26 27 28 26 26 26 26 21	22 20 21 21 21 21 21 23 24 26 28 26 22	20 22 21 19 21 22 20 20 24 24 23 23 23	21 21 22 21 21 21 23 23 24 23 23 23	21 23 22 23 20 20 20 20 20 25 23 20 22 22 22	22 20 22 19 23 22 20 22 22 21 25 21 21
$\begin{array}{c} 23\\ 23\\ 22\\ 24\\ 23\\ 25\\ 24\\ 24\\ 24\\ 22\\ 22\\ 22\\ 22\\ 22\\ H = \end{array}$	23 22 23 22 26 23 24 22 24 22 24 22 23 - 4	$25 \\ 23 \\ 24 \\ 24 \\ 24 \\ 23 \\ 24 \\ 23 \\ 24 \\ 23 \\ 22 \\ 22$	23 24 23 25 27 26 26 25 24 24 24 24 24 24 24 24	24 26 26 28 44 47 41 32 28 31 30 29 = 0 1	23 24 26 34 89 140 106 59 41 37 36 38 NTE	22 26 26 46 135 186 204 146 69 51 36 30 NSIT	$23 \\ 26 \\ 27 \\ 33 \\ 56 \\ 144 \\ 189 \\ 206 \\ 215 \\ 132 \\ 53 \\ 38 \\ 30 \\ Y = 5$	24 26 31 39 59 128 184 204 214 213 60 32 27 625	26 26 35 46 59 109 172 199 211 213 64 30 27 $\sigma = 22$	27 32 41 49 62 73 106 162 187 155 52 29 25	29 31 40 47 56 52 50 57 71 61 36 27 27	27 29 33 40 37 38 32 28 26 29 26 24 26	25 27 28 31 28 25 24 26 24 23 24 26 23	26 24 23 25 24 24 22 23 23 23 23 24	23 22 23 25 23 22 22 22 22 24 24 25 22	23 22 27 22 25 22 22 22 22 22 21 23 22 22 22 22 22
(b)	C fil	lm	10	10	20	21	20	20	20	10	30	21	20	20	20	10
20 20 20 20 20 19 20 18 19 20 18 19 20 18 19 20 18 19 22 H = 10	19 19 18 20 20 21 19 20 20 18 18 19 20 - 5	$ \begin{array}{r} 18 \\ 19 \\ 20 \\ 20 \\ 20 \\ 20 \\ 20 \\ 20 \\ 19 \\ 19 \\ 19 \\ 19 \\ 19 \\ 18 \\ K = - \end{array} $	19 21 20 20 20 21 21 19 20 21 20 21 20 21 20 19 20 21 20 21 20 21 20 21 21 20 20 20 20 20 20 20 20 20 20 20 20 20	$ \begin{array}{r} 19 \\ 18 \\ 20 \\ 21 \\ 20 \\ 20 \\ 20 \\ 18 \\ 19 \\ 18 \\ 21 \\ 19 \\ 18 \\ 21 \\ 19 \\ 18 \\ 21 \\ 19 \\ 18 \\ 21 \\ 19 \\ 18 \\ 21 \\ 19 \\ 18 \\ 21 \\ 19 \\ 18 \\ 21 \\ 19 \\ 18 \\ 21 \\ 19 \\ 18 \\ 21 \\ 19 \\ 18 \\ 21 \\ 19 \\ 18 \\ 21 \\ 19 \\ 18 \\ 21 \\ 19 \\ 18 \\ 21 \\ 19 \\ 18 \\ 21 \\ 19 \\ 18 \\ 21 \\ 19 \\ 18 \\ 21 \\ 19 \\ 18 \\ 21 \\ 19 \\ 10 \\$	20 19 21 20 20 21 22 21 20 20 20 20 20 20 20 20 20 20	21 19 21 22 23 20 21 20 18 19 FENS	20 19 22 25 22 23 22 19 20 20 20 22 17Y =	20 20 21 23 22 26 23 24 21 22 20 20 20 20 20 20 21 23 24 21 23 24 21 23 24 21 22 26 23 24 21 23 24 25 26 23 24 25 26 27 26 27 26 27 26 27 26 27 27 27 27 26 27 27 27 27 27 27 27 27 27 27	20 20 21 22 23 24 23 21 22 20	20 20 20 22 22 22 23 20 21 20 22 20 19	20 20 22 20 21 21 22 22 21 19 22 20 19	21 17 18 20 19 19 19 20 20 21 20 18 18	20 21 20 22 22 22 18 20 21 20 19 20 21	20 21 18 18 19 20 20 20 20 18 19 21 21 20	20 19 18 19 20 18 19 21 21 21 19 18 19	19 18 18 20 19 20 21 20 19 20 20 19 18
$ \begin{array}{r} 19\\ 16\\ 22\\ 19\\ 20\\ 19\\ 21\\ 20\\ 18\\ 19\\ 18\\ 22\\ H = \end{array} $	19 21 23 20 20 21 19 18 21 19 21 19 21 0 <i>K</i>	$20 \\ 20 \\ 21 \\ 21 \\ 23 \\ 20 \\ 20 \\ 20 \\ 22 \\ 20 \\ 18 \\ 21 \\ = -6$	18 20 22 26 26 27 28 26 24 23 20 21 19 	21 22 26 32 36 41 45 38 32 28 23 22 19 = 0	20 23 27 37 46 57 62 54 42 32 20 20 NTE	20 25 32 46 58 79 80 74 62 40 27 21 22 NSIT	20 26 34 52 70 88 94 95 77 57 35 26 20 Y = 3	19 23 32 48 72 91 102 102 92 71 47 24 21 277	$21 \\ 20 \\ 30 \\ 51 \\ 68 \\ 92 \\ 104 \\ 104 \\ 93 \\ 76 \\ 50 \\ 26 \\ 23 \\ \sigma = 2^{0}$	18 22 25 39 60 82 98 97 95 74 44 27 23	19 22 25 32 51 67 80 91 79 58 37 25 22	23 21 26 36 49 57 60 54 41 28 24 20	21 19 20 21 24 31 37 36 35 28 24 23 20	23 20 20 23 23 25 26 24 25 24 21 20	20 20 19 21 22 20 22 21 22 24 20 19	19 18 19 20 19 22 18 22 22 21 21 21 22 23
22 23 24 25 23 22 24 21 24 21 20 22 <i>H</i> -	24 23 24 25 28 25 23 24 25 22 22 23 24	$ \begin{array}{c} 24\\ 25\\ 31\\ 32\\ 39\\ 40\\ 36\\ 29\\ 23\\ 22\\ 21\\ 22\\ 22\\ 5\\ K = 0 \end{array} $	26 28 39 56 67 75 74 50 33 26 22 22 22	28 36 50 90 114 115 100 56 31 23 24 23	29 40 62 112 146 162 159 93 41 30 27 23	31 40 84 133 168 184 192 197 176 67 35 31 27 NSIT	33 38 68 132 174 194 203 211 211 98 47 35 31	31 38 54 123 170 203 212 217 178 56 40 34	31 34 47 92 154 184 201 211 217 204 69 41 36	26 28 40 66 130 169 206 213 201 65 39 33	24 26 30 50 99 142 177 196 205 167 57 35 31	26 21 28 34 60 103 149 172 177 98 46 29 25	25 20 24 26 37 62 94 115 102 66 36 25 22	21 23 25 26 34 46 62 54 36 27 22 21	19 23 22 23 22 24 29 30 29 24 23 20 21	24 21 22 23 22 21 23 21 22 22 22 22 22 22 21

agreement could only be investigated for the second group.

The variance of an integrated intensity has been evaluated in different ways. Seven laboratories did not report $\sigma(I)$ in their data sets. The statistical formulae used by the other eight laboratories are given in Table 4.

Estimation of the background comprises use of rectangles, frames, strips or boxes positioned outside the integration area. However, in most cases, the areas selected for background measurement lie as strips on two opposite sides of the reflection. In many systems the positioning and size of the area for background estimation can be selected *via* input instructions making the system flexible for different types of reciprocal lattice. The reflection positions were submitted by ten laboratories (*cf.* Table 4). This calculation is not normally included in the users' routine systems but was requested in order to detect errors due to the orientation matrix. However, the available (x, y) values were found to differ too much to be useful for statistical analyses in this project.

Preliminary treatment of the data

The data were submitted on punched cards or, in a few cases, on magnetic tape. All calculations within the project were performed on a DEC 10 computer. After storage of the submitted data on disc, the material was edited, and a few values with obvious errors were eliminated.

About 33000 individually measured intensities and, in addition, 17000 scaled intensities were stored as 86 data sets, in general six for each participant, as specified in Table 5. Table 6 shows the number of reflections contributed to the project by each participant. The *B* data set of participant No. 12 was damaged in transit and had to be totally rejected. Participant No. 10 submitted intensities only from films *C* and *D*.

As the user indications of supersaturated reflections or insignificant reflections varied from case to case and the absolute intensity scale also differed considerably between the experiments, a prescaling and editing program was written. The scale factors obtained between the different experiments varied from 0.24 to 2980.* One unit of intensity corresponds to about 250 photons, assuming that OD = 1 is the blackening obtained by 0.5 photon/ μ m² (Morimoto & Uyeda, 1963) using Ilford Industrial G film and Mo K α radiation.

The number of reflections submitted varies considerably (cf. Table 6), e.g. from 426 to 783 for the A film. This variation is due to different ways of defining a significance level. Some of the participants only submitted reflections which they considered significant, while others included all measurements. In a few cases it appeared that certain reflections had been rejected by the participants after inspection of their data sets.

For data sets which did not include standard deviations, $\sigma(I)$ values were estimated by comparison with the results from other laboratories after the data sets had been placed on a common scale. In the subsequent statistical analyses, only reflections with $I > 3\sigma(I)$ were considered significant. Due to the different ways in which $\sigma(I)$ was defined, the number of reflections used (Table 5, colums ii) varies from case to case. When comparing the precision of the different experiments in the following sections, these variations should be borne in mind.

Internal consistency

For each film the agreement between symmetry-related reflections was defined as

$$R_{\text{sym}} = \frac{\sum\limits_{hk} \sum\limits_{s} |I_{hk,s} - I_{hk}|}{\sum\limits_{hk} s I_{hk}}, \qquad (1)$$

where s is the number of symmetry-related reflections (s=4 for h, k>0; s=2 for h=0 or k=0), thus giving the degree of

* A complete list of the submitted intensities has been deposited with the British Library Lending Division as Supplementary Publication No. SUP 35089 (82 pp.). Copies may be obtained through The Executive Secretary, International Union of Crystallography, 5 Abbey Square, Chester CH1 2HU, England.

Table	3.	Μ	licrod	ensit	ometer	systems
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	On-line/		Core	Speed of
Exp.	off-line	Program	requirement	program
no.	system	language	(kbyte)	(reflections/min)
1	On-line	Algol 6	24	35
2	Off-line	Fortran IV	200	260
3	Off-line	Fortran IV	246	240
4	On-line	Fortran IV	64	32
5	*	-	-	_
6	On-line	Fortran II	32	30
		assembler		
7	On-line	Fortran IV	220	40
		assembler		
8	Off-line	Fortran IV	116	70
9	On-line	Fortran macro	28	48
10	On-line	Fortran macro	24	70
11	On-line	Assembler	32	70
12	Off-line	Fortran II	24	15
		assembler		
13	Off-line	Fortran IV	320	120
14	On-line	Fortran IV	56	50
		assembler		
15	On-line	Assembler	16	15
		* Manual microdensite	ometer.	

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Table 5. Naming of the different data sets

Data obtained from	Data set name
Film A, small spots, long exposure time	A
Film B, small spots, short exposure time	В
Film C, large spots, long exposure time	С
Film D, large spots, short exposure time	D
Scaled data, A to B	Ε
Scaled data. C to D	F

Table 6. A summary of the total number of intensities submitted (columns i) and the number of significant observations (columns ii)

Exp.	Fili	m A	Fil	m <i>B</i>	Fil	m C	Fil	m D	Set	Ε	Set	F
	i	ii	i	ii	i	ii	i	ii	i	ii	i	ii
1	587	273	236	142	614	448	275	260	580	270	611	443
2	426	317	362	218	552	472	441	316	421	309	543	456
3	552	268	562	179	589	416	566	287	533	260	582	411
4	720	368	720	237	719	470	720	323	720	365	719	465
5	492	442	345	313	489	488	367	360	474	440	486	486
6	783	362	788	237	822	481	823	332	774	355	813	330
7	691	344	704	229	708	486	712	367	687	311	702	455
8	653	544	669	602	487	467	645	310	652	522	589	446
9	722	287	722	186	720	370	720	231	720	263	719	330
10		-	-	-	717	478	718	319	-	-	715	465
11	556	287	317	191	662	449	453	310	575	291	651	426
12	660	385	-	-	550	444	439	297	663	381	543	426
13	520	327	221	167	565	463	185	185	345	339	360	354
14	671	336	704	243	677	435	706	343	611	330	643	431
15	575	353	576	205	590	507	583	452	570	330	575	503

Table 7. Intervals used for analysis of agreement factors

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			(appro:	x. max.)
Range	Min.	Max.	A/B set	C/D set
1	0	200	0.49	0.38
2	200	400	0.59	0.47
3	400	700	0.85	0.54
4	700	1300	1.29	0.71
5	1300	2400	2.0	0.99
6	2400	3500	2.9	1.39
7	3500		>3	> 1.50

internal consistency. The variation of R_{sym} with the intensity has been investigated using the intensity intervals listed in Table 7.

Tables 8 and 9 show the results from the A and C data sets respectively. Figs. 2–5 illustrate the R_{sym} distributions for all experiments. The number of reflections in each interval is also indicated. It is apparent that the films with smaller spots resulted in worse agreement between symmetry-related reflections. The statistical spread for the weak reflections is generally quite high. Some of the experiments show a slight increase in R for the strongest intensities (cf. Figs. 2–5), while in other experiments the R values fall off and converge towards a limiting value. The tendency to increase indicates systematic errors to be discussed later.

The user-scaled data sets (E and F) were also analysed in order to investigate differences in the R_{sym} distribution. The internal consistency of data sets E and F (Figs. 6 and 7) is closely related to that of data sets A and C (Figs. 2 and 4). By using Hamilton, Rollett & Sparks's (1965) scaling procedure (program SCALE), the A and B, and C and D data sets, respectively, have been scaled together to obtain film-factor values for each experiment.

Table 4. Technical details

с, Ц	Scanning are each reflectio	a of n (mm)	How is the orientation of the film pattern	How are non-lincarities in the OD measured and	Delivered xy position	The variance of each reflection is evaluated
ЦО.	Film A, B	Film C, D	established?	corrected for?	on films?	according to
1	0.65×0.75	1.05×1.15	Least-squares refinement	$D = D_m(1 - e^{-\alpha t})$	Yes	
7	$1 \cdot 1 \times 1 \cdot 1$	1.05×1.15	Least-squares refinement	Calibration table	Yes	$\operatorname{Var}(I) = \operatorname{Var}(B)\left[N_i + N_i^2/N_b\right]$
ę	1.7×1.7	2.1×2.3	Least-squares refinement	$I_c = I_m + (I_m/19)^2$	Yes	$Var(I) = 2(P_{OD} + B_{OD} - 10t_{OD})^2(N_b/N_l)^2$
4	1.2×1.2	1.2×1.2	Least-squares refinement	Three-degree polynomial	No	$\operatorname{Var}(I) = \Sigma(P_{\text{OD}} + B_{\text{OD}} - I \operatorname{ot}_{\text{OD}})^{*}(N_{b}/N_{i})^{*}$
5	Not given	Not given	Least-squares refinement	Calibration curve	No.	$Var(I) = 2(P_{OD} + B_{OD} - I Ol_{OD})^{2}(N_{b}/N_{i})^{2}$
9	0.6×0.6	1.0×1.0	Least-squares refinement	$I_c = I_m + (I_m/46)^3$	Yes	$\operatorname{Var}(I) = \operatorname{Var}(B)[N_i + N_i^2/N_b]$
5	1.1×0.9	1.5×1.2	Least-squares refinement	$I_c = A + BI_m + CI_m^2 + DI_m^3$	Yes	$\operatorname{Var}(I) = \operatorname{Var}(P) + (N_i/N_b)^2 \operatorname{Var}(B)$
~~~~~~~~~~~~~~~~~~~~~~~~~~~~~~~~~~~~~~~	$0.8 \times 0.8$	$0.8 \times 0.8$	Manual measurement	$I_c = A + BI_m + CI_m^2 + DI_m^3$	Yes	$\operatorname{Var}(I) = \operatorname{Var}(P) + (N_i/N_b)^2 \operatorname{Var}(B)$
6	$1 \cdot 1 \times 1 \cdot 1$	$1.5 \times 1.5$	Least-squares refinement	$D = D_m (1 - e^{-\alpha t})$	Yes	$\operatorname{Var}(I) = \Sigma P_{OD} + (N_i/N_b)^2 \Sigma B_{OD}$
10	$1 \cdot 1 \times 1 \cdot 1$	$1.9 \times 1.3$	Least-squares refinement	Four-degree polynomial	No	$\operatorname{Var}(I) = \Sigma P_{OD} + (N_i/N_b)^2 \Sigma B_{OD}$
11	$1.1 \times 0.9$	$1.9 \times 1.7$	Automatic search	Parabolic scaling	Yes	$Var(I) = \sum P_{OD} + (N_i/N_b)^2 \ge B_{OD}$
12	$1.1 \times 0.9$	$1.9 \times 1.7$	Adjusted using 15 reflections	Parabolic scaling	Yes	$Var(I) = \Sigma P_{OD} + (N_{i}/N_{b})^{2} \Sigma B_{OD}$
13	$1 \cdot 1 \times 1 \cdot 1$	1.1 × 1.1	Least-squares refinement	Parabolic scaling	No	From variations in $K_{sym}$
14	$1.3 \times 2.3$	$1.3 \times 1.5$	Least-squares refinement	Parabolic scaling	No	$Var(I) = E[(2P_{OD})^2 + (N_i/N_b)^2(2B_{OD})^2]$
15	$0.5 \times 0.5$	$1.4 \times 1.0$	Least-squares refinement	Parabolic scaling	Yes	Statistically from repeated measurement

# Table 8. R values from A-film data sets based on symmetry-related reflections

 $R_{\text{sym}}$  values (all reflections) and R values from different intensity intervals.

Exp.								
no.	$R_{\rm sym}$	$R_1$	R ₂	$R_3$	$R_4$	R ₅	$R_6$	$R_{\gamma}$
1	0.102	0.174	0.111	0.101	0.081	0.074	-	_
2	0.080	0.095	0.111	0.094	0.071	0.069		-
3	0.063	0.088	0.088	0.080	0.064	0.048	*	_
4	0.065	0.147	0.112	0.098	0.076	0.043	*	_
5	0.073	0.163	0.118	0.120	0.077	0.040	*	-
6	0.055	0.126	0.093	0.078	0.053	0.044	*	
7	0.076	0.112	0.107	0.099	0.085	0.056	*	_
8	0.104	0.213	0.215	0.159	0.090	0.056	*	_
9	0.058	-	0.128	0.103	0.095	0.077	0.055	0.032
10	-	-	-	-		-	-	-
11	0.078	0.119	0.112	0.093	0.086	0.050	*	-
12	0.063	0.119	0.109	0.089	0.060	0.042	*	-
13	0.065	0.090	0.073	0.070	0.062	0.048	*	
14	0.098	0.173	0.133	0.102	0.089	0.053	*	_
15	0.070	0.101	0.093	0.092	0.053	0.070	*	

* Non-significant number of reflections in the interval.



Fig. 2.  $R_{sym}$  values plotted against the intensity. All experiments from A film set.

# Table 9. R values from C-film data sets based on symmetry-related reflections

 $R_{\text{sym}}$  values (all reflections) and R values from different intensity intervals.

Exp.								
no.	R _{sym}	$R_1$	$R_2$	$R_3$	R4	R ₅	R ₆	R ₇
1	0.073	0.157	0.109	0.087	0.071	0.054	0.071	*
2	0.066	0.099	0.088	0.087	0.064	0.063	0.051	0.063
3	0.043	0.061	0.061	0.051	0.040	0.038	0.029	0.045
4	0.070	0.159	0.117	0.087	0.081	0.066	0.064	0.062
5	0.054	0.143	0.112	0.105	0.049	0.048	0.040	0.042
6	0.058	0.126	0.083	0.076	0.064	0.057	0.054	0.047
7	0.065	0.182	0.128	0.083	0.066	0.065	0.054	0.054
8	0.062	0.172	0.140	0.098	0.063	0.057	0.048	0.054
9	0.061	-	0.087	0.086	0.069	0.059	0.056	0.048
10	0.062	0.132	0.124	0.077	0.057	0.056	0.053	0.052
11	0.069	0.159	0.125	0.088	0.071	0.063	0.049	0.068
12	0.054	0.105	0.074	0.070	0.062	0.055	0.048	0.047
13	0.069	0.116	0.106	0.094	0.084	0.065	0.057	0.056
14	0.070	0.148	0.114	0.091	0.069	0.063	0.049	0.066
15	0.057	0.065	0.063	0.061	0.053	0.048	*	-

* Non-significant number of reflections in the interval.





By using a  $R_{sca}$  value defined as

$$R_{\rm sca} = \sum_{hk} |I_1 - kI_2| / \frac{1}{2} \sum_{hk} (I_1 + kI_2), \qquad (2)$$

where k is the film factor and  $I_1$  and  $I_2$  are intensities from the two successive films, an analysis of the consistency between the stronger and weaker data sets may be performed. The results obtained when scaling B to A and D to C are given in Tables 10 and 11, respectively.  $R_{sym}$  values were calculated for symmetry-related reflections from the average intensity files, *i.e.* the E and F files, and the files corresponding to data sets E and F but created in our scaling procedure. For experiments 11 to 15 which use the parabolic scaling method, it has not been possible to calculate film factors, k, or  $R_{sca}$  values, since the A-D intensities are not corrected for non-linearity. The  $R_{sym}$  values were thus only obtained from the original data sets E

The film factor between the B and A films varied from 2.58 to 3.20 except in two extreme cases (experiments 5 and 8 which

had values of 2.13 and 1.08). For the D to C data sets the variation was 2.60 to 3.21. If the film factor for experiments 5 and 8 for scaling of B to A were excluded, average values of 2.90 and 3.00 for scaling of B to A and D to C, respectively, were obtained. The scale factors for films A and B with the smaller spots are thus systematically too low, indicating inaccuracies in the non-linearity corrections and the Wooster (1964) effect.

# Mutual consistency

One measure of mutual inter-laboratory consistency for two experiments (i) and (j) is

$$R_{\rm mut} = \sum_{hk} |I_i - I_j| / \frac{1}{2} \sum_{hk} |I_i + I_j| , \qquad (3)$$

where  $I_i$  and  $I_j$  are on the same scale, a mutual scale factor being refined for each  $R_{mut}$  value. Table 12 shows the  $R_{mut}$ values from set *E*. It is obvious that experiments 5 and 8



Fig. 4  $R_{sym}$  plotted against the intensity. All experiments from C film set.

contain systematic errors, as indicated by the internal consistency test. The values of  $R_{mut}$  from the F set (Table 13) show that experiments 5, 8 and 15 differ slightly from the others.

Another way of assessing the mutual consistency is to analyse each experiment against an average value intensity file. All experiments were therefore scaled together using Hamilton, Rollett & Sparks's (1965) scaling procedure to establish two average files, one from the E and one from the Fsets.

The individual intensity weights in the scaling procedure were based on  $\sigma(I)$  (estimated as described previously if not given) in combination with the intensity according to

$$\sigma_{\rm ind} = \left[ \sigma(I)^2 + cI_i^2 \right]^{1/2}, \tag{4}$$

where c is a constant.

In order to obtain proper weights, c was varied to give the best value for the parameter 'goodness of fit' in the program SCALE (cf. Hamilton, Rollett & Sparks, 1965). The value

c=0.023 was used in the final averaging procedure and the corresponding weight analyses are given in Tables 14 and 15.

In the preparation of the final average intensity file from the E data sets, experiments 5 and 8 were rejected. The average file created from the F data sets was prepared from data from all 15 laboratories. These two average files were analysed for internal consistency, and the results are shown in Tables 16 and 17 and Fig. 8. Standard deviations for the average intensities could then be calculated from the statistical distribution of the observations, *i.e.* 

$$\sigma_{\rm av}(\bar{I}) = \left[\sum_{i} (I_i - \bar{I})^2 / (N - 1)\right]^{1/2}.$$
 (5)

For each experiment (i),  $R_{av}$  values were also calculated, where  $R_{av}$  is defined as

$$R_{av} = \sum_{hk} |I_i - \overline{I}| / \sum \overline{I} .$$
 (6)

 $I_i$  is an individual integrated intensity in the E or F data sets



Fig. 5.  $R_{sym}$  values plotted against the intensity. All experiments from D film set.

and  $\overline{I}$  is the average intensity value obtained from the scaling procedure (cf. Tables 14 and 15 and Figs. 9 and 10). Generally, the quantity  $|I_i - \overline{I}|$  is smaller than  $|I_i - I_j|$  which should be kept in mind when comparing  $R_{mut}$  and  $R_{av}$ .

# Analysis of variance

The analysis of variance was performed with the program HANOVA (Hamilton, 1964; Abrahams, Alexander, Furnas, Hamilton, Ladell, Okaya, Young & Zalkin, 1967; Abrahams, Hamilton & Mathieson, 1970). The parameters chosen for the analysis were the experiment number n with effect E(n), the intensity range I with effect I(I), the angular range  $2\theta$  with effect  $A(2\theta)$  and the symmetry related quadrants Q with effect Q(q). The latter effect was included in order to locate errors in the positioning of the microdensitometers. Thus, the model for the analysis of variance used is

$$w_{hi}(I_{hi} - I_h) = \mu + M + EI + EA + EQ + \varepsilon, \qquad (7)$$

where  $I_h$  is the average intensity with index hk0,  $I_{hi}$  is the intensity of reflection hk0 for the *i*th participant,  $w_{hi}$  is a weight defined in (10) and (11),  $\mu$  is the overall mean (approximately zero), M is the sum of the main effects, E, I, A and Q, EI is an experiment – intensity interaction effect, EA is an experiment – angular interaction effect, EQ is an experiment – quadrant interaction effect, and  $\varepsilon$  is a normally distributed random error.

The  $\mathbf{F}$  distribution is the basis for most of the multivariate hypothesis tests and is the distribution of the ratio of two estimates of the same variance. One may assume that the weighted deviations from the average intensity,

$$X_{hi} = (I_{hi} - I_{h}) w_{hi}, \qquad (8)$$

has a normal random distribution for each experiment, *i.e.* that EI, EA and EQ are zero. To investigate this assumption, the F ratio may be calculated:



Fig. 6.  $R_{sym}$  values plotted against the intensity. All experiments from E data sets.

$$\mathbf{F}_{v_1,v_2} = \left[\sum_{i} n_i (\bar{X}'_i - \bar{X}'')^2 / v_1\right] / \left[\sum_{h} \sum_{i} (X_{hi} - \bar{X}'_i)^2 / v_2\right], \quad (9)$$

where

$$\bar{X}^{''} = \sum_{h} \sum_{i} X_{hi} / \sum_{i} n_{i}, \ \bar{X}_{i}' = \sum_{h} X_{hi} / n_{i},$$
$$v_{1} = k - 1, \ v_{2} = \sum_{i} n_{i} - k$$

and  $n_i$  is the number of observations in each of the k experiments (cf. Larson, 1975). The F distribution for normal populations with the same variance has been tabulated for different degrees of freedom,  $v_1$  and  $v_2$ , at different levels of significance,  $\alpha$ . If the observed value of  $\mathbf{F}_{v_1,v_2}$  exceeds the tabulated  $\mathbf{F}_{v_1,v_2,\alpha}$  value, the variances of the compared populations are not equal at the chosen level of significance, *i.e.* EI, EA or EQ in (7) are not zero for all experiments. It is only relevant to analyse the E and F data sets, since only these

sets have been corrected for non-linearity in all experiments. It is essential to introduce proper weights in (8), and two different weighting schemes have been tested:

$$w_{hi} = (I_h)^{-1} \,. \tag{10}$$

$$w_{hi} = (\sigma_{\text{ind},hi})^{-2}, \qquad (11)$$

where  $\sigma_{ind,hi}$  is defined by (4). The use of either (10) or (11) resulted only in slightly different values of the calculated F ratio and did not affect the conclusions concerning the experiments. Weights according to (11) were used in the following calculations.

In the execution of the HANOVA program, the E data sets 5 and 8 were excluded, since a preliminary execution showed large EI and EQ effects for these two experiments. As the E data set 10 was not submitted, there are only 12 E data sets included in (9). Since each of the investigated interaction



Fig. 7.  $R_{sym}$  values plotted against the intensity. All experiments from F data sets.

# Table 10. Agreements between symmetry-related reflections from the scaled data sets E

The values in parentheses were obtained in our scaling procedure.

<b>F</b>	$R_{\rm sca}$	T:1								
Exp. no.	films	factor	Room	$R_1$	$R_{2}$	R ₃	R₄	R ₅	Re	R-
1	0.096	3.20	0.103	0.179	0.109	0.098	0.081	*	_	
	0 070	0 20	(0.071)	(0.072)	(0.109)	(0.068)	(0.098)			
2	0.110	2.78	0.072	0.115	0.102	0.086	0.072	0.056	*	
			(0.076)	(0.142)	(0.136)	(0.083)	(0.076)	(0.055)		
3	0.064	2.95	0.066	0.088	0.085	0.082	0.063	0.062	0.054	
			(0.067)	(0.086)	(0.090)	(0.085)	(0.064)	(0.063)	(0.055)	
4	0.104	2.58	0.065	0.149	0.106	0.094	0.078	0.045	*	-
			(0.071)	(0.152)	(0.130)	(0.095)	(0.090)	(0.045)		
5	0.171	2.13	0.075	0.188	0.116	0.102	0.077	0.047	*	
			(0.081)	(0.197)	(0.123)	(0.104)	(0.080)	(0.050)		
6	0.061	2.89	0.057	0.128	0.087	0.077	0.060	0.046	0.033	-
			(0-057)	(0-128)	(0.087)	(0.077)	(0.060)	(0.046)	(0.033)	
7	0.058	2.89	0.074	0.116	0.112	0.092	0.080	0.057	0.056	
			(0.080)	(0.132)	(0.145)	(0.094)	(0.087)	(0.057)	(0.053)	
8	0.357	1.08	0.076	0.181	0.101	0.084	0.081	0.045	0.054	
			(0.092)	(0.218)	(0.141)	(0.117)	(0.088)	(0.055)	(0.056)	
9	0.072	2.98	0.089	-	0.0103	0.082	0.072	0.036	0.043	
			(0.065)		(0.104)	(0.074)	(0.092)	(0.040)	(0.046)	
10	-	-	-		_	-	-	-	-	~
11	-	-	0.076	0.118	0.112	0.090	0.088	0.057		-
12	-	-	0.070	0.116	0.104	0.092	0.065	0.048		
13	-	-	0.067	0.088	0.074	0.070	0.063	0.050		-
14	-		0.092	0.151	0.126	0.101	0.091	0.060		-
15	-	-	0.068	0.104	0.090	0.087	0.020	0.064		

* Non-significant number of reflections in the interval.

# Table 11. Agreement between symmetry-related reflections from the scaled data sets F

The values in parentheses were obtained in our scaling procedure.

Evn	R _{sca}	Film								
no.	films	factor	Ram	$R_1$	R,	R ₃	R ₄	Rs	$R_{6}$	$R_7$
1	0.074	3.20	0.071	0.157	0.105	0.076	0.075	0.072	0.051	*
•	00/1	5 20	(0.075)	(0.115)	(0.115)	(0.073)	(0.059)	(0.075)	(0.043)	*
2	0.061	3.21	0.056	0.100	0.084	0.069	0.057	0.051	0.045	0.055
-			(0.058)	(0.093)	(0.106)	(0.071)	(0.053)	(0.058)	(0.045)	(0.055)
3	0.050	2.84	0.045	0.063	0.056	0.037	0.029	0.031	0.040	0.052
	0.000		(0.048)	(0.082)	(0.069)	(0.039)	(0.034)	(0.039)	(0.041)	(0.053)
4	0.084	3.08	0.073	0.153	0.131	0.087	0.077	0.076	0.066	0.063
			(0.074)	(0.164)	(0.140)	(0.089)	(0.075)	(0.077)	(0.072)	(0.062)
5	0.116	2.60	0.059	0.163	0.128	0.084	0.065	0.061	0.043	0.046
-			(0.059)	(0.170)	(0.119)	(0.086)	(0.056)	(0.065)	(0.044)	(0.046)
6	0.058	3.12	0.061	0.117	0.110	0.065	0.074	0.075	0.044	0.052
			(0.061)	(0.117)	(0.110)	(0.065)	(0.074)	(0.075)	(0.044)	(0.052)
7	0.085	2.90	0.068	0.218	0.138	0.090	0.072	0.054	0.050	0.059
			(0.068)	(0.192)	(0.130)	(0.098)	(0.054)	(0.072)	(0.050)	(0.059)
8	0.106	2.92	0.066	0.172	0.143	0.132	0.079	0.063	0.051	0.051
			(0.073)	(0.178)	(0.151)	(0.127)	(0.065)	(0.121)	(0.051)	(0.051)
9	0.050	3.02	0.061		0.084	0.071	0.069	0.056	0.062	0.058
			(0.061)		(0.083)	(0.068)	(0.055)	(0.071)	(0.062)	(0.058)
10	0.068	3.13	0.065	0.141	0.147	0.080	0.055	0.057	0.053	0.058
			(0.066)	(0.143)	(0.158)	(0.084)	(0.056)	(0.057)	(0.053)	(0.058)
11	_	-	0.066	0.142	0.116	0.088	0.070	0.061	0.045	0.60
12	-	-	0.057	0.110	0.073	0.069	0.060	0.057	0.050	0.049
13	-	_	0.071	0.119	0.104	0.096	0.084	0.064	0.056	0.054
14	-	-	0.070	0.136	0.113	0.096	0.081	0.070	0.050	0.056
15	-		0.056	0.061	0.060	0-058	0.054	0.049	*	-

* Non-significant number of reflections in the interval.

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Table 12. Inter-experimental  $R_{mut}$  factors for E data set

Exp.																	Exp.
no.	1	2	3	4	5	6	7	8	9	10	11	12	13	14	15	R _{mut}	no.
1		0.106	0.110	0.103	0.296	0.109	0.116	0.224	0.107	-	0.095	0.124	0.094	0.135	0.133	0.126	1
2			0.063	0.098	0.230	0.070	0.080	0.166	0.064	-	0.075	0.085	0.071	0.094	0.091	0.093	2
3				0.096	0.212	0.048	0.078	0.142	0.064	-	0.069	0.091	0.070	0.092	0.096	0.095	3
4					0.225	0.099	0.097	0.171	0.097	-	0.117	0.079	0.075	0.095	0.086	0.111	4
5						0.247	0.208	0.266	0.231	-	0.241	0.196	0.214	0.210	0.158	0.226	5
6							0-061	0.123	0.047	-	0.070	0.116	0.080	0.088	0.114	0.098	6
7								0.112	0.055	-	0.073	0.091	0.062	0.080	0.089	0.092	7
8									0.110	-	0.151	0.237	0.146	0.168	0.201	0.171	8
9										-	0.066	0.112	0.072	0.079	0.097	0.092	9
10												~	-	-	-		10
11												0.126	0.085	0.094	0.119	0.106	11
12													0.080	0.094	0.080	0.116	12
13														0.089	0.086	0.094	13
14															0.100	0.109	14
15																0.112	15

# Table 13. Inter-experimental $R_{mut}$ factors for F data set

Exp. no.	1	2	3	4	5	6	7	8	9	10	11	12	13	14	15	<b>R</b> _{mut}	Exp. no.
1		0.084	0.075	0.062	0.138	0.070	0.087	0.098	0.063	0.072	0.072	0.067	0.083	0.070	0.139	0.084	1
2			0.049	0.050	0.118	0.047	0.071	0.075	0.053	0.054	0.064	0.059	0.071	0.061	0.114	0.069	2
3				0.061	0.080	0.054	0.048	0.050	0.048	0.045	0.049	0.045	0.046	0.053	0.092	0.057	3
4					0.121	0.057	0.071	0.081	0.053	0.056	0.057	0.100	0.071	0.061	0.143	0.075	4
5						0.117	0.094	0.092	0.093	0.107	0.121	0.108	0.111	0.122	0.080	0.107	5
6							0.062	0.071	0.040	0.045	0.049	0.074	0.064	0.057	0.117	0.066	6
7								0.055	0.051	0.056	0.049	0.055	0.063	0.065	0.083	0.065	7
8									0.057	0.059	0.073	0.083	0.065	0.068	0.093	0.073	8
9										0.039	0.043	0.061	0.058	0.054	0.103	0.058	9
10											0.053	0.063	0.060	0.051	0.109	0.062	10
11												0.071	0.084	0.062	0.107	0.068	11
12													0.049	0.052	0.080	0.069	12
13														0.064	0.99	0.071	13
14															0.106	0.068	14
15																0.105	15

Table 14.	Scaling	of the	Ε	data	sets
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Weighting scheme and R values for each experiment against the average-intensity file.

		Tota	l I				
	Interval	numb	er	Average			
	no.	of reflect	tions	intensity	⟨w⊿²⟩	$R_{\rm av,tot}$	
	1	1282	2	153	0.873	0.154	
	2	1138	3	285	1.019	0.145	
	3	800		508	0.925	0.098	
	4	694		926	1.035	0.076	
	5	707		1744	0.917	0.055	
	6	124		2652	0.864	0.089	
	7	21		3683	1.317	0.382	
Exp.							
no.	Rav	$R_1$	R ₂	$R_3$	R ₄	$R_5$	$R_{6}$
1	0.085	0.172	0.112	0.076	0.048	0.096	
2	0.052	0.129	0.089	0.059	0.033	0.032	
3	0.047	0.101	0.070	0.046	0.039	0.036	
4	0.066	0.127	0.112	0.081	0.045	0.056	0.138
5	0.210	0.170	0.412	0.342	0.284	0.122	0.232
6	0.058	0.128	0.078	0.057	0.062	0.030	0.077
7	0.046	0.098	0.066	0.065	0.039	0.027	
8	0.184	0.238	0.319	0.170	0.093	0.052	0.090
9	0.054	-	0.100	0.057	0.039	0.029	0.074
10	-	-	-		_		
11	0.071	0.133	0.101	0.072	0.032	0.062	0.122
12	0.073	0.140	0.149	0.115	0.076	0.044	0.073
13	0.048	0.098	0.089	0.052	0.042	0.029	
14	0.065	0.170	0.125	0.071	0.050	0.026	
15	0.070	0.123	0.146	0.095	0.072	0.058	0.058

effects *EI*, *EA* and *EQ* is divided into four levels (cf. Table 18), the  $v_1$  number of degrees of freedom is  $12 \times 4 - 1 = 47$ . Correspondingly,  $v_2 = 59$  for the *F* data sets, all of which were used in the analysis. The observed  $\mathbf{F}_{v_1,v_2}$  ratios, calculated according to (9), have been compared with the values tabulated on the 0.005 level of significance. If the observed

			Total					
	Inte	rval	number	Average				
	no	o. of	f reflections	intensity	<pre>w</pre>	$1^2$ R	av,101	
	1		1328	149	0.6	54 0-	158	
	2		1369	282	1.0	23 0-	128	
	3	<b>,</b>	795	533	1.0	03 0.	080	
	4	Ļ	1133	979	0.9	18 0-	051	
	4	5	588	1828	0.9	81 O·	032	
	e	j	486	3003	0.9	65 O·	027	
	7	7	728	4627	0.8	80 0.	040	
Exp								
no.	Ray	$R_1$	$R_2$	R ₃	R ₄	$R_5$	R ₆	$R_7$
1	0.060	0.197	0.121	0.109	0.062	0.025	0.034	0.052
2	0.048	0.131	0.093	0.079	0.057	0.030	0.029	0.041
3	0.028	0.092	0.064	0.040	0.027	0.015	0.017	0.027
4	0.062	0.197	0.106	0.074	0-048	0.032	0.027	0.072
5	0.083	0.218	0.208	0.196	0.082	0.037	0.091	0.056
6	0.043	0.116	0.118	0.071	0.039	0.023	0.023	0.044
7	0.039	0.150	0.148	0.082	0.052	0.027	0.026	0.020
8	0.050	0.208	0.188	0.100	0.056	0.035	0.030	0.038
9	0.034	-	0.126	0.076	0.036	0-026	0.020	0.026
10	0.036	0.158	0.111	0.048	0.036	0.030	0.019	0.028
11	0.045	0.155	0.133	0.078	0.043	0.037	0.027	0.037
12	0.046	0.193	0.064	0.043	0.050	0.040	0.023	0.046
13	0.043	0.133	0.094	0.076	0.062	0-045	0.028	0.020
14	0.041	0.174	0.129	0.063	0.048	0.029	0.019	0.016
15	0.089	0.232	0.424	0.213	0.100	0.000	0.024	0.0.0

Table 15. Scaling of the F data sets

Weighting scheme and R values for each experiment against the average-intensity file.

Table 16. Internal consistency analysis of the average-intensity file created from the E sets

R _{sym}	$R_1$	$R_2$	$R_3$	R4	$R_5$	$R_6$	$R_7$
0.057	0.088	0.082	0.068	0.058	0.040	0.036	

Table 17. Internal consistency analysis of the average-intensity file created from the F sets

$R_{\rm sym}$	$R_1$	$R_2$	$R_3$	$R_4$	R ₅	R ₆	$R_7$
0.050	0.064	0.061	0.057	0.052	0.049	0.036	0.031



Fig. 8. (a) Internal consistency for the average intensity file from the E data sets. (b) Internal consistency for the average intensity file from the F data sets.

 $\mathbf{F}_{v_1,v_2}$  ratio exceeds the tabulated  $\mathbf{F}_{v_1,v_2,0\cdot005}$  value, the hypothesis that there are no systematic differences between the experiments may be rejected. The probability of rejecting a true hypothesis is then less than 0.5 %.

Table 18. Level intervals for the multivariate hypothesis tests

E data sets				
Variable I $A(2\theta)$ Q	Level 1 0-250 0-12 h > 0, k > 0	Level 2 250-750 12-18 h > 0, k < 0	Level 3 750-1500 18-26 h < 0.k > 0	Level 4 1500– 26- h < 0.k < 0
F data sets Variable I $A(2\theta)$ Q	Level 1 0-300 0-12 <i>h</i> >0, <i>k</i> >0	Level 2 300–900 12–18 h>0,k<0	Level 3 900–2000 18–26 h<0,k>0	Level 4 2000- 26- h < 0, k < 0

The tabulated values for the two sets of data, *E* and *F*, are  $\mathbf{F}_{47,4719,0.005} = 1.67$  and  $\mathbf{F}_{59,6370,0.005} = 1.65$ , respectively. We now assume that all data sets are identical and formulate the following hypotheses:

*Hypothesis* 1. The experiment-intensity interaction effects, EI, are zero, *i.e.* the error distributions are the same within the four intensity levels for all experiments. The calculation gave  $F_{47,4719} = 4.81$  for the *E* data sets and  $F_{57,6370} = 3.08$  for the *F* data sets. Thus, the above hypothesis may be strongly rejected for both sets of data. The rejection of this hypothesis means that there are systematic errors in one or more of the experiments, as was also indicated by the  $R_{mut}$  and  $R_{av}$  values.

*Hypothesis* 2. The experiment-angular effects, *EA*, are zero, *i.e.* there are no systematic differences between the experiments depending on the  $2\theta$  angle. The observed  $F_{47,4719}$  and  $F_{59,6370}$  values are 1.17 and 0.98 for the *E* and *F* data sets, respectively. Thus, the above hypothesis cannot be rejected either for the *E* sets nor for the *F* sets.

In the third test it was investigated whether or not there was



Fig. 9. Interval R values ( $R_{av}$ ) calculated from the deviation of each experiment from the average-value file. E data sets.

any interaction between the experiment number and the symmetry quadrants on the films.

*Hypothesis* 3. Experiment-quadrant interaction effects, EQ, are zero, *i.e.* the error distributions are identical in the four quadrants for all experiments. The calculation gave  $F_{47,4719} = 3.53$  for the *E* data sets and  $F_{57,6370} = 0.94$  for the *F* data sets. The hypothesis cannot be rejected for the *F* sets as  $F_{57,6370,0.005} = 1.67$  but can be rejected for the *E* data sets with a high degree of confidence. One or more experiments in the *E* set thus have systematic errors due to the scanner positioning.

The estimates of the four levels for each of the three variables EI, EA and EQ have been plotted explicitly in Figs. 11 and 12 for each of the data sets.

#### Discussion

In the previous sections, the quality of each measurement has been investigated. Different R values, defined according to

formulae (1), (2), (3) and (6), have been used to analyse the spread in the intensity measurements. Furthermore, each data set has been investigated in different intervals of intensity and angular distribution in order to examine the internal consistency of each densitometer system. These interval R values have been plotted against the magnitude of intensity for the different data sets A, B, C and D (in Figs. 2–5). The shapes of the curves differ from laboratory to laboratory but are often similar for the A and B data sets on one hand and for the C and D sets on the other. The data from the average intensity value files show high internal consistency, giving a good idea of the accuracy attainable with microdensitometer systems. Data from most of the participants are also homogeneous even if there are some differences in the individual results which will be commented on in this section.

### General effects due to spot size

It is clearly demonstrated that the statistical spread of the intensities measured on films with small spots (A, B) is greater



Fig. 10. Interval R values ( $R_{av}$ ) calculated from the deviation of each experiment from the average-value file. F data sets.

than that obtained from films with large spots (C, D). Due to the logarithmic relationship between optical density, D, and the ratio of the incident to the transmitted microdensitometer light beam,

$$D = \log_{10}(I_0/I), \qquad (11)$$

it is impossible to obtain an accurate value of D when the blackening of the illuminated area is not uniform. This effect was pointed out by Wooster (1964) 'If the density variation across the field of view is small then the average intensity of the transmitted light will be nearly given by the average density. For a large variation of density much inaccuracy is introduced'. Fig. 13(a) and (b) shows the distribution of Rvalues in different intensity intervals obtained when comparing the individual E and F data sets with the corresponding average-value files. The significant increasing trend in  $\bar{R}$ values for strong intensities for the E data set (cf. Table 14) is not generally seen when testing the individual data sets with respect to symmetry-related reflections (Fig. 6). This effect is due to the different ways in which non-linearity corrections have been performed, together with errors due to Wooster effects. The corresponding effect for the F data sets is much smaller but still present (Fig. 13b and Table 15).



## Differences between experiments: set E

The overall F ratios show that there are systematic differences between the data sets, regardless of whether the analysis is carried out with respect to the intensity (EI), angular  $2\theta$  (EA), or symmetry-quadrant (EQ) distribution. The partial F distributions in each level investigated are plotted and described in Fig. 11 and those experiments which

 Table 19. Deviations from the average values on the 0.005 significance level (cf. Figs. 11 and 12)

5

E data sets

F dat

	Effect	Exp. no.
	EI	5, 8, 9, 11, 12, 15
	EA EQ	1. 8
a sets		
	Effect	Exp. no.
	EI	5, 8, 15

ΕA

ΕQ



Fig. 12. Interaction effects derived by analysis of variance for the F data sets. There were four levels for each factor, as indicated in Table 18. Error bars  $2\sigma$  in length, where  $\sigma$  is the estimated standard deviation of the corresponding effect as derived from the analysis of variance least-squares program, are given at the foot of the figure.

have systematic errors on the 0.005 significance level are listed in Table 19. An individual **F** ratio for each of the experiments is shown in Fig. 14.

It is apparent that experiments 5 and 8 suffer from errors which are much larger than for the other experiments in the *E* data set. This is also evident from the inter-experimental agreement factors ( $R_{mut}$ , Table 12) and the agreement with the average values ( $R_{av}$ , Table 14). When inspecting the intensity data from experiment 5 it is apparent that the weak reflections are too strong and the strong reflections too weak. It has not been possible to determine the reason for this from information available.

Experiment 8 also shows poor agreement with the other experiments. When inspecting the intensity data, reflections which should be systematically absent or very weak were found to have relatively high values, sometimes greatly exceeding  $3\sigma(I)$ . The overestimate was not constant, but varied considerably. It is therefore reasonable to assume that significant reflections are also biased with a varying, positive value. This is verified by a comparison with the other experiments. The error may arise from an underestimate of the background value.

Experiment 9 has been rejected with respect to EI effects in Table 19 since there were no reflections in the first intensity interval (cf. Fig. 2). The standard deviations provided by this laboratory were generally two to three times higher than the others and the weakest reflections from the first intensity interval were therefore excluded by our  $3\sigma(I)$  significant test.

Experiments 11, 12 and 15 contribute most to the increasing trend of the R value for the strongest reflections (Fig. 13). This is also apparent from Table 14 in which the results from interval analysis of each experiment are compared with the average-value file.



The high experiment-quadrant interaction shown by experiment 1 is probably accidental and due to a positioning error in the least-squares procedure for calculating the transformation matrix, since the analysis of variance test on the C, D and F data sets did not show the same effect. Experiment 8 also had too high an EQ interaction term. This could be due to an accidental mistake in the manual determination of the orientation of the film pattern.

### Differences between experiments: set F

The analysis of variance tests for the F data sets is generally better than for the E sets. Fig. 12 shows plots of the four levels of the factors EI, EA and EQ. Experiments with significant deviations at the 0.005 level are indicated in Table 19. Again, experiments 5 and 8 are seen to differ from the average intensity file for the same reasons as in the E set. For experiment 15 it can be seen from Fig. 10 and Table 15 that  $R_{av}$ for the first and especially for the second intensity intervals have unexpectedly high values. Similar deviations, although not as pronounced, are found for the E set (cf. Table 14). This is probably due to a software error.

#### Comparison between on-line and off-line systems

From the internal and mutual consistency tests a comparison can be made between on-line and off-line systems. Experiments 5 and 8 have been rejected from the E set. Average R values for each of the on-line and off-line groups from the internal and mutual consistency tests are presented in Table 20.



 

 Table 20. Average R values obtained from E and F data sets for on-line and off-line systems

	$R_{sym}$		R	mut	$R_{\rm av}$		
System	E set	F set	E set	F set	E set	F set	
On-line Off-line	0·077 0·067	0·064 0·061	0.091 0.087	0.070 0.065	0·048 0·045	0-064 0-057	



Fig. 13. The total distribution of R values  $(R_{totax})$  for the E data sets. (b) The total distribution of R values  $(R_{totax})$  for the F data sets.

Fig. 14. Individual  $\mathbf{F}$  values indicating the relative magnitudes of the systematic errors associated with the E data sets.

The average values of  $R_{sym}$ ,  $R_{mut}$  and  $R_{av}$  for the off-line systems are all somewhat lower than those for the on-line systems. This may indicate that off-line systems yield more reliable data, since they can often utilize greater core memory and thus make use of more extensive program systems. However, if experiments 1 and 15 (both on-line systems) are excluded, since they were rejected by the program HANOVA, the R values for the on-line group become almost identical with those of the off-line group. Assuming that the discrepancy for experiments 1 and 15 is accidental, one may then conclude that on-line and off-line systems are equally accurate. On the other hand, experiments 1 and 15 may indeed reflect the difficulties inherent in obtaining a reliable on-line software package, especially when only a small core memory is available.

#### Comparison between different scaling procedures

Average R values were also calculated for the groups of participants using parabolic scaling or numerical correction of each density value (cf. Table 21) in order to correct for nonlinearity effects, followed by linear scaling. The R values indicate that the systems which use numerical correction for each optical density are generally in better agreement than those which use the parabolic scaling procedure. The average values for  $R_{sym}$  and  $R_{mut}$  are not as useful as  $R_{av}$  in this case.  $R_{sym}$ is based on symmetry-related reflections in the four quadrants, and is not affected by errors in the correction for non-linearity. Neither are the average values of  $R_{mut}$ , as given in Tables 12 and 13, useful. A new set of  $R_{mut}$  values was calculated separately for the two groups; parabolic or numerical, respectively. Then it became evident, as can be seen in Table 22, that the accuracy is better for users of numerical non-linear correction followed by linear scaling of the two films.

Table 21. Average R values from E and F sets for the two groups parabolic scaling (exp. nos. 10–15) and linear scaling (exp. nos. 1–9) after numerical non-linearity correction

	R _{sym}		R	mut	$R_{av}$		
System	E set	F set	<i>E</i> set	F set	E set	F set	
Parabolic	0.075	0.064	0.091	0.075	0.065	0.053	
Linear	0.071	0.062	0.088	0.064	0.058	0.044	

Table 22. Modified average  $R'_{mut}$  values, calculated separately, for the groups of parabolic and linear scaling

	R' _{mut}				
System	E set	F set			
Parabolic	0.095	0.077			
Linear	0.084	0.058			

The parabolic scaling procedure should not be used on films with different spot sizes (e.g. Weissenberg films and oscillation films). If, however, films with constant spot sizes are scanned, the parabolic scaling procedure, properly weighted, may have advantages in minimizing Wooster effects.

# The average microdensitometer data

In the analysis of the individual E and F data sets, we have found a concordant group of experiments with a relatively good internal homogeneity. By using this data, average intensity files have been created.

As stated previously, only experiments 5 and 8 were rejected from the E data set, even though the analysis of variance indicated that other experiments from both sets were affected by systematic errors. On the other hand, an F ratio calculation on the 0.005 significance level is a very sensitive test and deletion of more experiments could lead to successive rejections. The two average-value files from each data set E and F have been analysed as being separate experiments. The results from the internal consistency test on the two files is shown in Tables 12 and 13 and Fig. 9. The  $R_{svm}$  values obtained from the two files (0.057 and 0.050 for  $\vec{E}$  and F, respectively) appear to be satisfactory. Both crystals used in this project gave  $R_{sym}$  values of 0.050 for corresponding hk0reflections measured with a Syntex P21 diffractometer. Further comparison with diffractometer data will be given in Report II.

The agreement between the weak reflections is generally better for the average files than for any of the individual experiments, which is to be expected if the errors are mainly randomly distributed.

# Size of light beam

It has been seen that films with small spot sizes give worse agreement than those with large spot sizes, due to the Wooster effect (*cf.* Tables 10 and 11). Normally, all films were measured with a light-beam size of  $100 \times 100 \,\mu$ m, but two participants, 6 and 7, used a raster size of  $50 \times 50 \,\mu$ m for the *A/B* film set. The results in Table 14 may indicate an improvement when the raster size is lowered to 50  $\mu$ m for the small spots. However, the *F* data sets 6 and 7 are also of good quality (Table 15) and it is not therefore possible to draw any definite conclusions.

## Choice of radiation and film

The principal difference between film and diffractometer methods is that films suffer from unfavourable build-up of background during data collection (Arndt, 1968). For this reason, it is advisable to use monochromatized radiation in order to reduce the background as much as possible.

The choice of film is also of great importance. In this project Ilford Industrial G film, which was recommended by Morimoto & Uyeda (1963), has been used. Unfortunately, this film is no longer manufactured. However, since the film quality is not one of the parameters of this project, it has no bearing on the present results. Another IUCr Commission on Crystallographic Apparatus project is investigating characteristics of X-ray films now available.

# Choice of microdensitometer and computer systems

As the main group of participants (12) in this project use an Optronics drum microdensitometer it is not possible to compare different types of scanners. There would seem to be no distinct difference in quality between on-line and off-line systems, and the choice between one or the other may therefore be dictated by the local situation.

### Evaluation of standard deviations

There are many different ways of evaluating the standard deviations, but two procedures dominate within this project, *i.e.* a quantum statistical expression (*cf.* experiments 3, 9, 14) and a scanner optics expression (*cf.* experiments 2, 6, 7). However, none of the estimates of a standard deviation of an intensity measurement, based on either of these two procedures reproduce the variation in intensity found in

practice. We have calculated the statistical standard deviation, defined as

$$\sigma_{\text{stat}} = \left[\sum_{i}^{n} (I_i - \overline{I})^2 / (n - 1)\right]^{1/2}, \qquad (12)$$

where  $\overline{I}$  is the average intensity,  $I_i$  is the scaled intensity value for the *i*th participant and *n* is the number of participants contributing to the average intensity value. The values of  $\sigma_{\text{stat}/I}$  have been estimated and averaged in different intensity intervals (cf. Fig. 15).



Fig. 15. The factors  $\sigma_{\text{stat}}/I$  and interval  $R_{\text{av}}$  plotted against the intensity.

Neither the quantum-statistics-related nor the scanneroptics-related standard-deviation expressions describe the curves found in Fig. 15, and especially the rising trend for the E data sets cannot be achieved. A reasonable calculation of  $\sigma(I)$  values may instead be based on a combination of the two different procedures, since they describe two independent effects. In addition, a third empirical term should be included to compensate for systematic errors such as Wooster effects.

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